

Search Notes

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TAN X. DINH

Applicant(s)/Patent under
Reexamination

ISHI ET AL.

Art Unit

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SEARCHED

Class	Subclass	Date	Examiner
369	13.13 13.33	11/16/2006	T.D

INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (see search history printout)	11/16/2006	T.D